

P-Channel JFETs

J174	SST174
J175	SST175
J176	SST176
J177	SST177

Product Summary

Part Number	V _{GS(off)} (V)	r _{Ds(on)} Max (Ω)	I _{D(off)} Typ (pA)	t _{ON} Typ (ns)
J/SST174	5 to 10	85	-10	25
J/SST175	3 to 6	125	-10	25
J/SST176	1 to 4	250	-10	25
J/SST177	0.8 to 2.25	300	-10	25

J/SST176, For applications information see AN104, page 21.

Features

- Low On-Resistance: J174 <85 Ω
- Fast Switching—t_{ON}: 25 ns
- Low Leakage: -10 pA
- Low Capacitance: 5 pF
- Low Insertion Loss

Benefits

- Low Error Voltage
- High-Speed Analog Circuit Performance
- Negligible "Off-Error," Excellent Accuracy
- Good Frequency Response
- Eliminates Additional Buffering

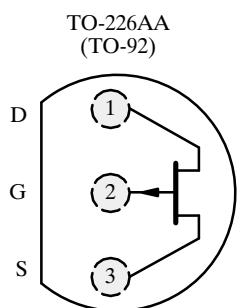
Applications

- Analog Switches
- Choppers
- Sample-and-Hold
- Normally "On" Switches
- Current Limiters

Description

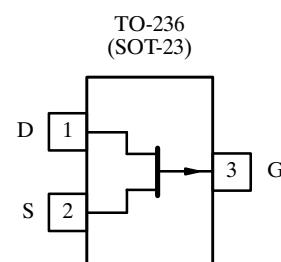
The J/SST174 series consists of p-channel analog switches designed to provide low on-resistance and fast switching. This series simplifies series-shunt switching applications when combined with the Siliconix J/SST111 series.

The TO-226AA (TO-92) plastic package provides a low-cost option, while the TO-236 (SOT-23) package provides surface-mount capability. Both the J and SST series are available in tape-and-reel for automated assembly (see Packaging Information).



Top View

J174
J175
J176
J177



Top View

SST174 (S4)*
SST175 (S5)*
SST176 (S6)*
SST177 (S7)*

*Marking Code for TO-236

Absolute Maximum Ratings

Gate-Drain Voltage	30 V
Gate-Source Voltage	30 V
Gate Current	-50 mA
Storage Temperature	-55 to 150°C
Operating Junction Temperature	-55 to 150°C

Lead Temperature (1/16" from case for 10 sec.)	300°C
Power Dissipation ^a	350 mW

Notes

a. Derate 2.8 mW/°C above 25°C

J/SST174 Series

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Specifications^a for J/SST174 and J/SST175

Parameter	Symbol	Test Conditions	Typ ^b	Limits				Unit	
				J/SST174		J/SST175			
				Min	Max	Min	Max		
Static									
Gate-Source Breakdown Voltage	V _{(BR)GSS}	I _G = 1 μA, V _{DS} = 0 V	45	30		30		V	
Gate-Source Cutoff Voltage	V _{GS(off)}	V _{DS} = -15 V, I _D = -10 nA		5	10	3	6		
Saturation Drain Current ^c	I _{DSS}	V _{DS} = -15 V, V _{GS} = 0 V		-20	-135	-7	-70	mA	
Gate Reverse Current	I _{GSS}	V _{GS} = 20 V, V _{DS} = 0 V T _A = 125°C	0.01 5		1		1	nA	
Gate Operating Current	I _G	V _{DG} = -15 V, I _D = -1 mA	0.01						
Drain Cutoff Current	I _{D(off)}	V _{DS} = -15 V, V _{GS} = 10 V T _A = 125°C	-0.01 -5		-1		-1		
Drain-Source On-Resistance	r _{DS(on)}	V _{GS} = 0 V, V _{DS} = -0.1 V			85		125	Ω	
Gate-Source Forward Voltage	V _{GS(F)}	I _G = -1 mA, V _{DS} = 0 V	-0.7					V	
Dynamic									
Common-Source Forward Transconductance	g _{fs}	V _{DS} = -15 V, I _D = -1 mA f = 1 kHz	4.5					mS	
Common-Source Output Conductance	g _{os}		20					μS	
Drain-Source On-Resistance	r _{ds(on)}	V _{GS} = 0 V, I _D = 0 mA, f = 1 kHz			85		125	Ω	
Common-Source Input Capacitance	C _{iss}	V _{DS} = 0 V, V _{GS} = 0 V, f = 1 MHz	20					pF	
Common-Source Reverse Transfer Capacitance	C _{rss}	V _{DS} = 0 V, V _{GS} = 10 V f = 1 MHz	5						
Equivalent Input Noise Voltage	ē _n	V _{DG} = -10 V, I _D = -1 mA f = 1 kHz	20					nV/ √Hz	
Switching									
Turn-On Time	t _{d(on)}	V _{GS(L)} = 0 V, V _{GS(H)} = 10 V See Switching Circuit	10					ns	
	t _r		15						
Turn-Off Time	t _{d(off)}		10						
	t _f		20						

Specifications^a for J/SST176 and J/SST177

Parameter	Symbol	Test Conditions	Typ ^b	Limits				Unit	
				J/SST176		J/SST177			
				Min	Max	Min	Max		
Static									
Gate-Source Breakdown Voltage	V _{(BR)GSS}	I _G = 1 μA, V _{DS} = 0 V	45	30		30		V	
Gate-Source Cutoff Voltage	V _{GS(off)}	V _{DS} = -15 V, I _D = -10 nA		1	4	0.8	2.25		
Saturation Drain Current ^c	I _{DSS}	V _{DS} = -15 V, V _{GS} = 0 V		-2	-35	-1.5	-20	mA	
Gate Reverse Current	I _{GSS}	V _{GS} = 20 V, V _{DS} = 0 V T _A = 125°C	0.01 5		1		1	nA	
Gate Operating Current	I _G	V _{DG} = -15 V, I _D = -1 mA	0.01						
Drain Cutoff Current	I _{D(off)}	V _{DS} = -15 V, V _{GS} = 10 V T _A = 125°C	-0.01 -5		-1		-1		
Drain-Source On-Resistance	r _{DS(on)}	V _{GS} = 0 V, V _{DS} = -0.1 V			250		300	Ω	
Gate-Source Forward Voltage	V _{GS(F)}	I _G = -1 mA, V _{DS} = 0 V	-0.7					V	

Specifications^a for J/SST176 and J/SST177

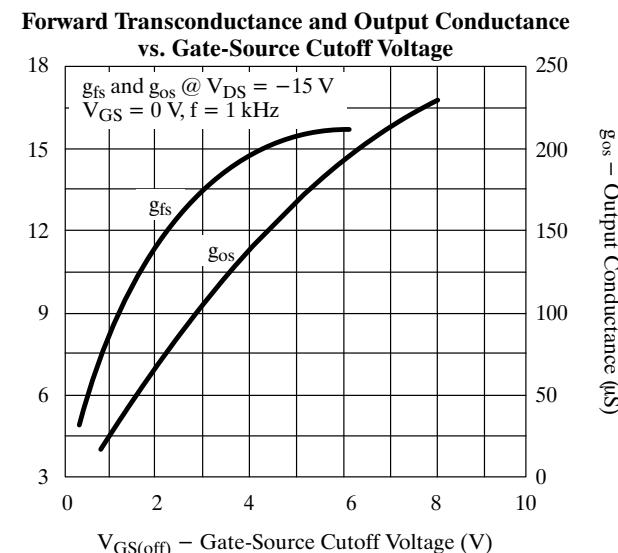
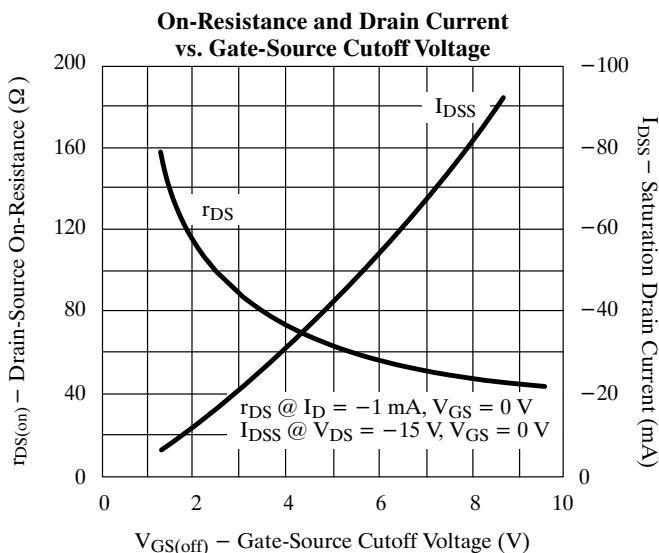
Parameter	Symbol	Test Conditions	Typ ^b	Limits				Unit	
				J/SST176		J/SST177			
				Min	Max	Min	Max		
Dynamic									
Common-Source Forward Transconductance	g_{fs}	$V_{DS} = -15 \text{ V}, I_D = -1 \text{ mA}$ $f = 1 \text{ kHz}$	4.5					mS	
Common-Source Output Conductance	g_{os}		20					μS	
Drain-Source On-Resistance	$r_{ds(on)}$	$V_{GS} = 0 \text{ V}, I_D = 0 \text{ mA}, f = 1 \text{ kHz}$			250		300	Ω	
Common-Source Input Capacitance	C_{iss}	$V_{DS} = 0 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	20					pF	
Common-Source Reverse Transfer Capacitance	C_{rss}	$V_{DS} = 0 \text{ V}, V_{GS} = 10 \text{ V}$ $f = 1 \text{ MHz}$	5						
Equivalent Input Noise Voltage	\bar{e}_n	$V_{DG} = -10 \text{ V}, I_D = -1 \text{ mA}$ $f = 1 \text{ kHz}$	20					$\text{nV}/\sqrt{\text{Hz}}$	
Switching									
Turn-On Time	$t_{d(on)}$	$V_{GS(L)} = 0 \text{ V}, V_{GS(H)} = 10 \text{ V}$ See Switching Circuit	10					ns	
	t_r		15						
Turn-Off Time	$t_{d(off)}$		10						
	t_f		20						

Notes

- a. $T_A = 25^\circ\text{C}$ unless otherwise noted.
b. Typical values are for DESIGN AID ONLY, not guaranteed nor subject to production testing.
c. Pulse test: $PW \leq 300 \mu\text{s}$ duty cycle $\leq 3\%$.

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Typical Characteristics

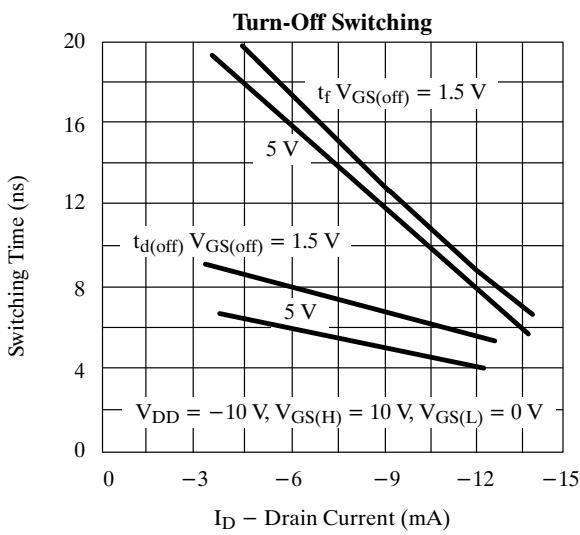
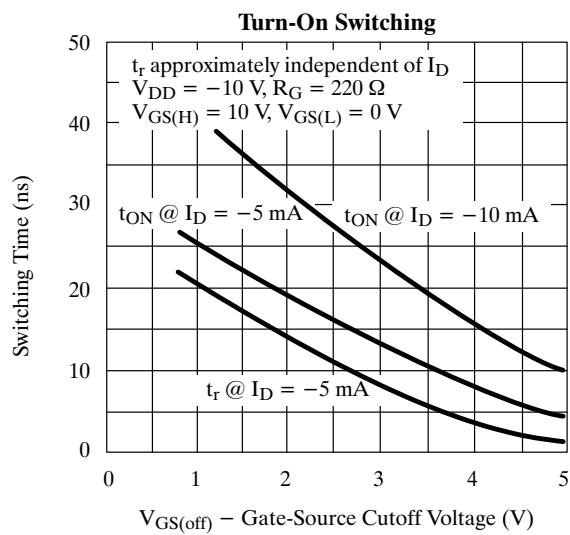
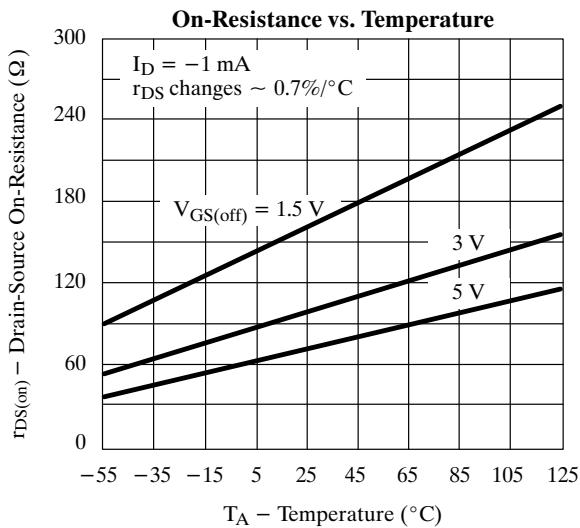
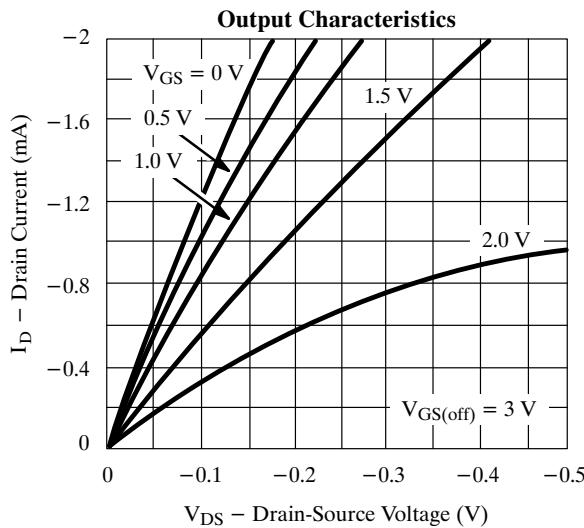
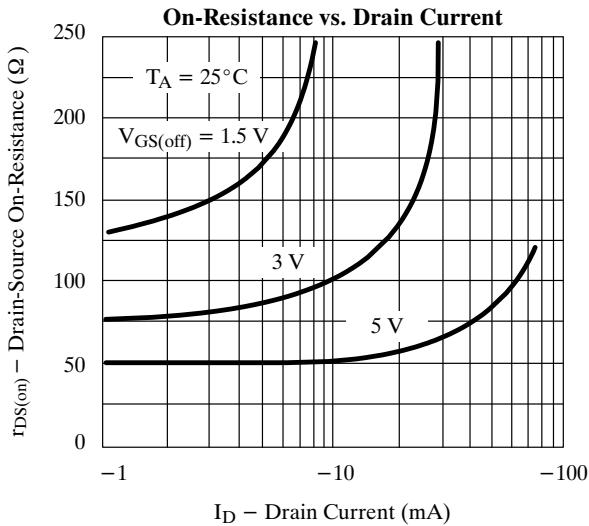
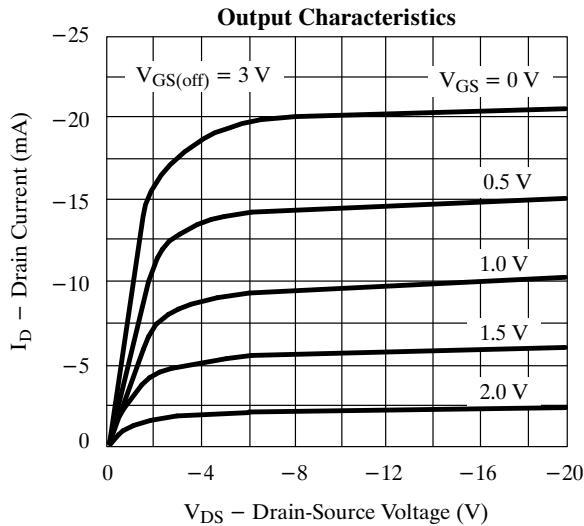


J/SST174 Series

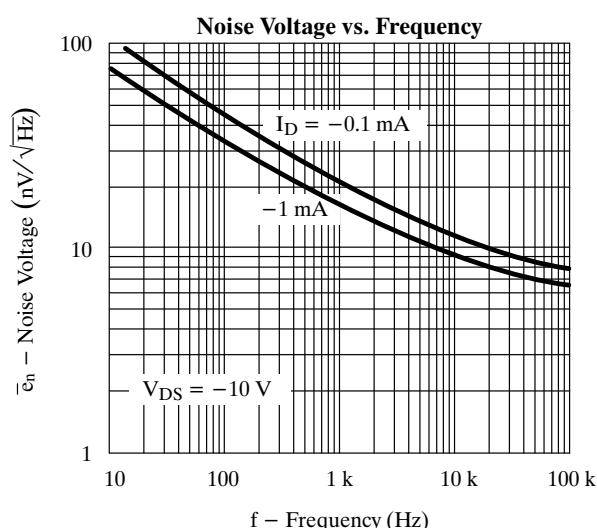
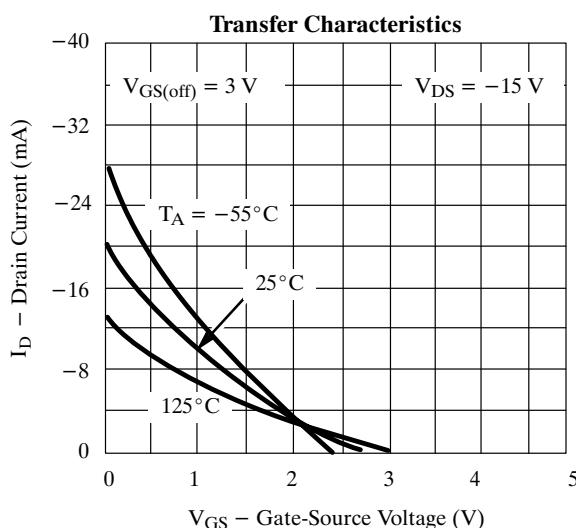
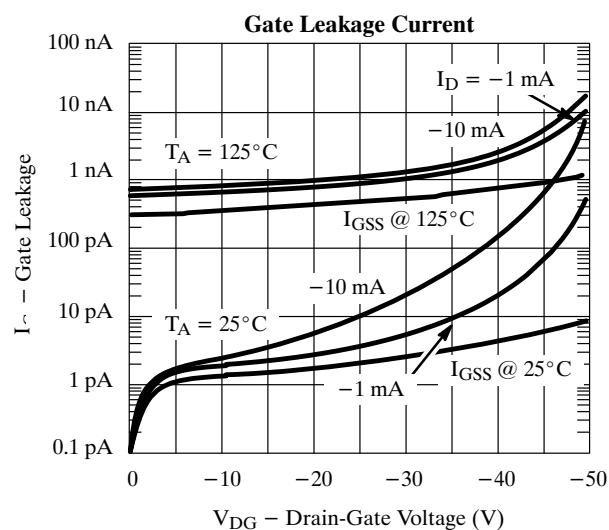
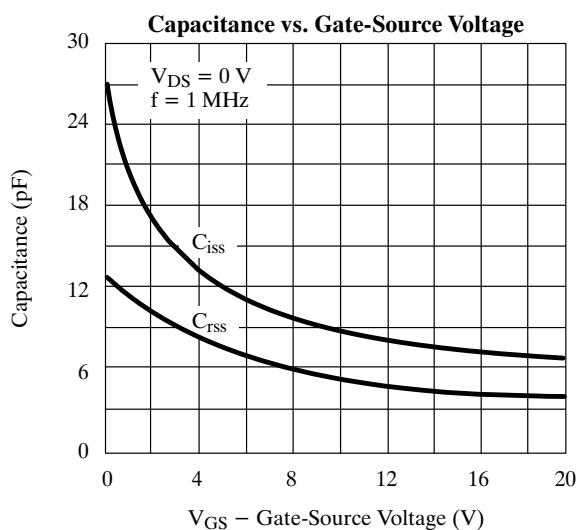
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Typical Characteristics (Cont'd)



Typical Characteristics (Cont'd)



Switching Time Test Circuit

	174	175	176	177
V _{DD}	-10 V	-6 V	-6 V	-6 V
V _{GG}	20 V	12 V	8 V	5 V
R _L *	560 Ω	750 Ω	1800 Ω	5600 Ω
R _G *	100 Ω	220 Ω	390 Ω	390 Ω
I _{D(on)}	-15 mA	-7 mA	-3 mA	-1 mA

*Non-inductive

Input Pulse

Rise Time < 1 ns
Fall Time < 1 ns
Pulse Width 100 ns
PRF 1 MHz

Sampling Scope

Rise Time 0.4 ns
Input Resistance 10 MΩ
Input Capacitance 1.5 pF

See Typical Characteristics curves for changes.

